# Contents

# 1. Summary

# 2. Agenda Officer's Announcement

Reviewed the status of the PAR and it was indicated that we did have the ability to extend some time. At the same time, it was accentuated that we would maintain our aggressive scheduling:

1. Draft for Comments (End Of January) based on the meeting
2. Review with comments (Prior to North Carolina meeting in May)

# 3. Introductions of Members and Guests (all) / Sign-In Sheet

Attendees: 18 members and guests, 10 members.

Attendance as follows:

Beske, Bryan(M); Chan, K.S.(M); Eblen, Marcia(M); Garrett, D. Lane(M); Greenfield, Steve(M); Haahr, Charles(G); Harger, Thomas(G); Havelka, Martin(M); Hobbs, Robert(G); Laird, Donald N.(M); Lemeilleur, Henri(M); McGann, Shawn(G); Nowell, Robert(G); Rorabaugh, Jesse(M); Rzasa, Michael(M); Sharifnia, Hamid(G); Steinman, Greg J.(M); Stidham, Curtis(M); Triantopoles, George(G); Kramshuster, Cris(G); Callsen, Thomas(G); Holm, Dan(G); Bucio, Ryan(G);

# 4. Review of IEEE Patent Disclosure (5 Slides)

The committee reviewed the IEEE Patent Disclosure as required when there is an active PAR.

# 5. Status of PAR

The PAR has been in place since June 12th, 2008 and is valid through December 2012. Considerations are in place regarding extending the PAR.

## 6. Meeting Goal 1 Further Clarify Figures 6-9

Conclusion:

- Figure 6: Standard Loop
- Figure 7: Paralleling
- Figure 8: Standard (exothermic specific)
- Figure 9: Paralleling (exothermic specific)
- Angle/Plate to be AL or CU
- Pass/Fail = all four of your four samples of a design pass
- Sample
    - 48” long sample
    - Rigid
        - Mention minimum deformation specification
    - EMF
        - Mid Span Test 24” +/- 1”
        - Termination Connection
            - A connector at each end bus
            - One connection tested at a time (other end is a dead-end)

## 7. Meeting Goal 2 Discuss the Cost of Testing

- Testing looks expensive, looking to apply the “1 second rating” to reduce cost of EMF
- Use of existing test data is permissible assuming the connector design still meets the same specification

## 8. Meeting Goal 3 Family Definition

- EMF
    - Copper Only
    - Largest to Largest
    - Largest to Smallest
- Sequential Test
    - Copper
    - Copperclad (if appropriate)
    - Largest to Largest
    - Largest to Smallest

## 9. Meeting Goal 4 Acid Pass/Fail Criteria

- Just do a Pull test for a ground rod
- Run a salt fog

Jesse will write up a proposal (it will be in End of January Draft)

## 10. Meeting Goal 5 EMF Cycle Criteria

- EMF Rating
  - Change to 1 second rating
  - 2 shots

## 11. Meeting Goal 6 Review Comments of current draft

- Topic deferred to include today's discussion

## 12. Meeting Goal 7 Next Steps

- Draft 8.6 For Review End Of February
- Online Comment End Of March
- Interim Review End Of April
- Final Review at Live March Meeting
- Submit to IEEE for June

## 13. General Notes

A series of WEBEX meetings will be scheduled to work through the remainder of the draft. ONCE complete, the draft will be loaded to the team site.

Team Site Notes:

Website: http://ewh.ieee.org/cmte/substations/

Protected File Password: e9837

## 14. Next Meeting

Next meeting to held in conjunction with the IEEE PES Annual meeting in May 2012. The location this year is Raleigh, NC the week of May 21st.